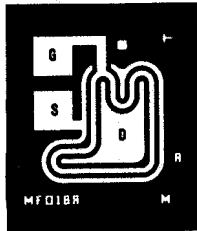


**P-CHANNEL ENHANCEMENT MOS FET**

CHIP NUMBER

**FMP1.1**



.023"  
(0.584mm)

.021"  
(0.533mm)

**CONTACT METALLIZATION**

Top Contact: > 12,000 Å Aluminum

Backside Contact: 3,000 Å Gold

**ASSEMBLY RECOMMENDATIONS**

It is advisable that:

- a) the die be eutectically mounted with gold silicon preform 98/2%.
- b) 1 mil (0.0254mm) aluminum wire be ultrasonically attached to the top contact.

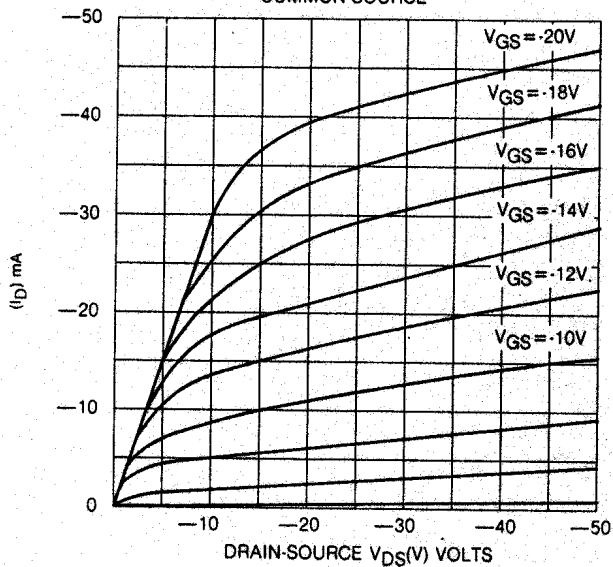
Die Size: 21 x 23 (mils)  
0.533 x 0.584(mm)  
Pad Size: 4 x 4 (mils)  
BODY-SUBSTRATE

**TYPICAL ELECTRICAL CHARACTERISTICS**

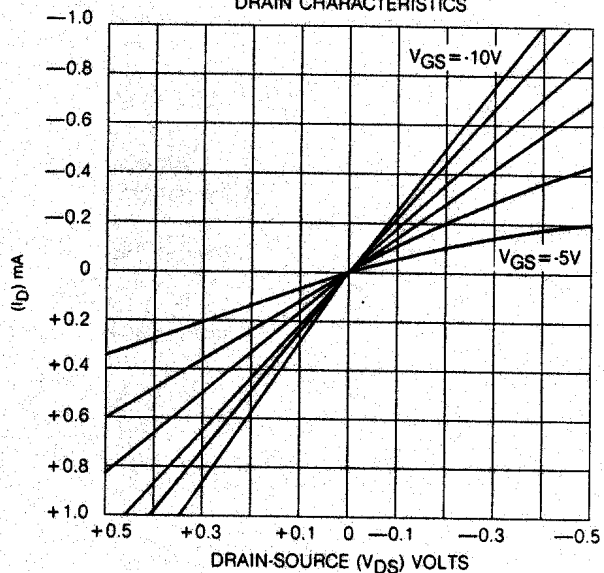
PARAMETER	MIN.	TYP	MAX.	UNIT	TEST CONDITIONS
BV <sub>GSS</sub>	-35	-40	-60	V	I <sub>D</sub> = 10, μA, V <sub>GS</sub> = 0, V <sub>BS</sub> = 0
I <sub>DSS</sub>		20	500	pA	V <sub>DS</sub> = -15V, V <sub>GS</sub> = 0, V <sub>BS</sub> = 0
g <sub>fs</sub>	1000	2500	4000	μmho	V <sub>DS</sub> = -15V, I <sub>D</sub> = 10mA, f = 1KHz
I <sub>D(on)</sub>	-3.0		-30	mA	V <sub>DS</sub> = -15V, V <sub>GS</sub> = -10V, V <sub>GS</sub> = 0
r <sub>DS</sub>		200	350	Ω	V <sub>GS</sub> = -20V, I <sub>D</sub> = -100μA, V <sub>BS</sub> = 0
V <sub>GS(th)</sub>	-2.0		-5.0	V	V <sub>DS</sub> = -15V, I <sub>D</sub> = -10μA, V <sub>BS</sub> = 0
C <sub>rss</sub>			1.0	pF	V <sub>DS</sub> = -15V, I <sub>D</sub> = -10mA, f = 1MHz
C <sub>iss</sub>			3.5	pF	V <sub>DS</sub> = -15V, I <sub>D</sub> = -10mA, f = 1MHz
e <sub>n</sub>		50		nV/√Hz	V <sub>DS</sub> = -15V, I <sub>D</sub> = -10mA, f = 1KHz

TYPICAL DEVICE TYPES: 2N4065, 3N163, 3N164, UC1700, UC1702

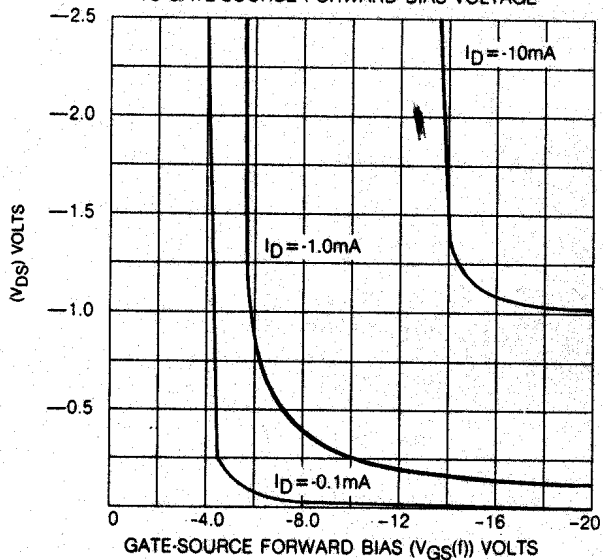
DRAIN CHARACTERISTICS—  
COMMON-SOURCE



LOW LEVEL  
DRAIN CHARACTERISTICS



LOW-LEVEL "ON" DRAIN SOURCE VOLTAGE  
VS GATE-SOURCE FORWARD BIAS



STATIC DRAIN-SOURCE ON RESISTANCE  
VS GATE-SOURCE FORWARD BIAS

